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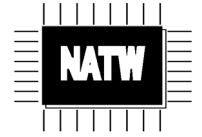
Karen Panetta – Tufts Univ.

12th IEEE North Atlantic Test Workshop NATW 2003



May 15-16, 2003

Guerney's Inn at the Sea
Montauk, New York, USA



Call for Papers

The IEEE North Atlantic Test Workshop provides a forum for discussions on the latest issues relating to high quality, economical, and efficient testing methodologies and designs. The 12th workshop will feature “*Test Challenges for the Deep Sub-Micron Era*”. The major topics include, but are not limited to, the following:

- Analog/Mixed Signal Testing
- Automatic Test Generation
- Built-In Self-Test (BIST)
- Board Level Testing
- Defect Oriented Testing
- Delay/Performance Testing
- Design for Testability
- Design Verification/Validation
- Diagnosis and Debug
- Embedded Core Testing
- Fault Modeling/Simulation
- IDDQ Testing
- Multi-Chip Module Testing
- Memory Testing
- MEMS Testing
- Online Testing
- System-on-Chip (SOC) Test
- System Testing
- Test Economics
- Test Quality/System Reliability
- Test Resource Partitioning
- Test Synthesis

The Program Committee invites authors to submit original, unpublished paper and panel proposals. Papers may be extended summaries of full papers. Detailed instructions for submission can be found at the **AUTHOR/REVIEWER** link at the NATW'03 web page (<http://www.ecs.umass.edu/natw>).

Student Presentation Session:

To encourage student participation in the research community, we will dedicate a session to high quality student presentations. We feel that it is important to integrate students into the research community early, so that they can experience the excitement of direct interaction with their peers. This session will provide students with the opportunity to get feedback on their research in an open atmosphere.

Important Dates:

Submission of papers	2/07/03
Notification of paper acceptance	3/21/03
Submission of camera-ready papers	4/18/03

For general information, contact:

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To see other information regarding this workshop, visit our homepage at:

<http://www.ecs.umass.edu/natw>